

FDS6894A

Dual N-Channel Logic Level PWM Optimized PowerTrench® MOSFET

General Description

These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Features

• 8 A, 20 V. $R_{DS(ON)} = 17 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$ $R_{DS(ON)} = 20 \ m\Omega \ @ \ V_{GS} = 2.5 \ V$

 $R_{DS(ON)} = 20 \text{ m}\Omega \text{ @ } V_{GS} = 2.3 \text{ V}$ $R_{DS(ON)} = 30 \text{ m}\Omega \text{ @ } V_{GS} = 1.8 \text{ V}$

• Low gate charge (17 nC)

- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- · High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		± 8	V
I _D	Drain Current - Continuous	(Note 1a)	8	А
	– Pulsed		32	
P _D	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T _J , T _{STG}	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W	
Raic	Thermal Resistance Junction-to-Case	(Note 1)	40	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6894A	FDS6894A	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		I	I	1	I
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	20			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			1 10	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.6	0.8	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{vmatrix} V_{GS} = 4.5 \text{ V}, & I_D = 8 \text{ A} \\ V_{GS} = 2.5 \text{ V}, & I_D = 7 \text{ A} \\ V_{GS} = 1.8 \text{ V}, & I_D = 6 \text{ A} \\ V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}, T_J = 125^{\circ}\text{C} \\ \end{vmatrix} $	3	13 16 21 18	17 20 30 25	mΩ
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 4.5V$, $V_{DS} = 5 V$	16			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 8 \text{ A}$		44		S
Dynamic	: Characteristics	1 36 m				
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		1676		pF
Coss	Output Capacitance	f = 1.0 MHz		288		pF
C _{rss}	Reverse Transfer Capacitance			146		pF
Switchir	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, I_{D} = 1 \text{ A},$		10	20	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		14	25	ns
$t_{d(off)}$	Turn-Off Delay Time			33	53	ns
t_{f}	Turn-Off Fall Time			12	22	ns
Q_g	Total Gate Charge	$V_{DS} = 10 \text{ V}, I_{D} = 8 \text{ A},$		17	24	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 4.5 V		2.8		nC
Q_{gd}	Gate-Drain Charge			3.3		nC
Drain-S	ource Diode Characteristics a	and Maximum Ratings				
Is	Maximum Continuous Drain-Source I				1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2)		0.7	1.2	V

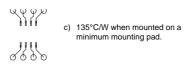
^{1.} R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 78°C/W when mounted on a 0.5in² pad of 2 oz copper



b) 125°C/W when mounted on a 0.02 in² pad of 2 oz copper



Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%

Typical Characteristics

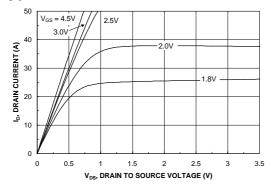
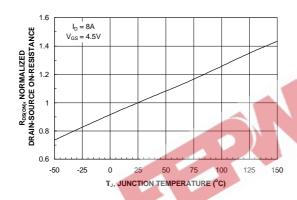


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



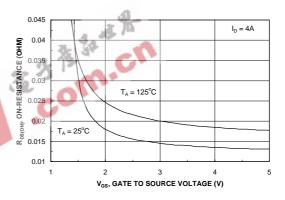
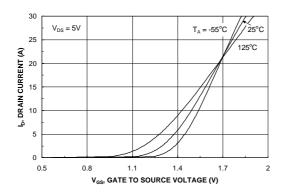


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



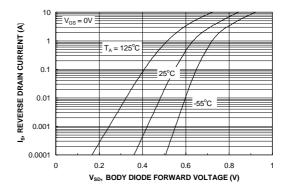
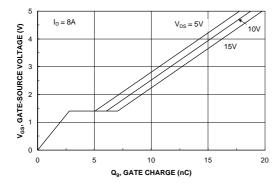


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



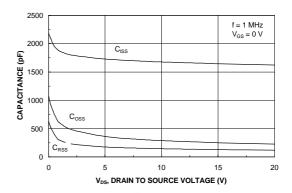


Figure 7. Gate Charge Characteristics.

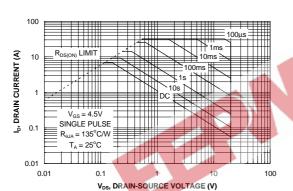


Figure 8. Capacitance Characteristics.

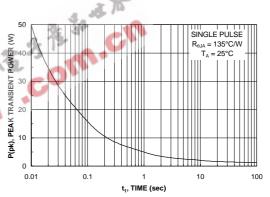


Figure 9. Maximum Safe Operating Area.



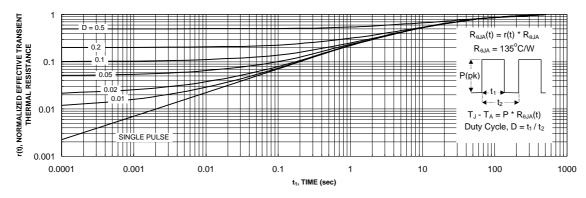


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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Rev. H4